Applicant(s)/Patent Under Application/Control No. Reexamination 10/772,651 SHIN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2815 Matthew E. Warren U.S. PATENT DOCUMENTS Document Number Country Code-Number-Kind Code Date Classification Name MM-YYYY 257/777 10-2000 Hikita et al. US-6,133,637 438/109 Derderian, James M. 05-2003 US-6,569,709 В 257/723 04-2001 Ozawa et al. US-6,215,182 C 264/272.11 08-2000 Scranton et al. US-6,099,783 D Ε US-US-F G US-Н US-USı US-J Κ US-US-L US-М FOREIGN PATENT DOCUMENTS Date Document Number Classification Name Country Country Code-Number-Kind Code MM-YYYY H01L 23/30 KONDO et al. Japan JP 63240053 A 10-1988 0 Р Q R S NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) W

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